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With the principle of “Quality Parts,Customers Priority,Honest Operation,and Considerate Service”,our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

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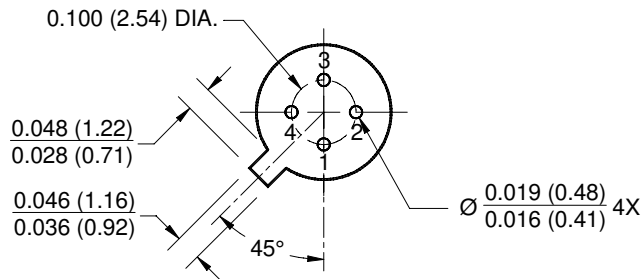
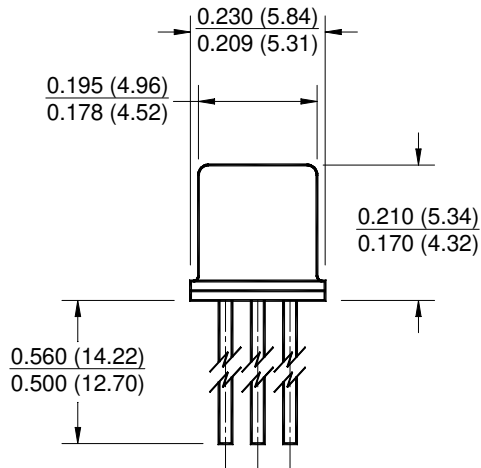
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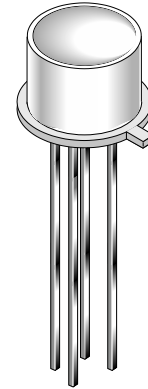


**PACKAGE DIMENSIONS**

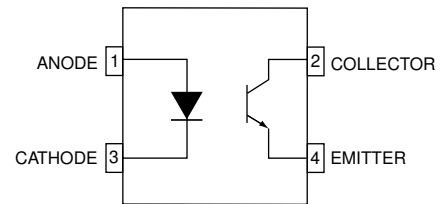


**NOTES:**

1. Dimensions for all drawings are in inches (mm).
2. Tolerance of  $\pm .010$  (.25) on all non-nominal dimensions unless otherwise specified.



**SCHEMATIC**



**DESCRIPTION**

The MCT4 is a standard four-lead, TO-18 package containing a GaAs infrared emitting diode optically coupled to an NPN silicon planar phototransistor.

**FEATURES**

- Hermetically package
- High current transfer ratio; typically 35%
- High isolation resistance;  $10^{11}$  ohms at 500 volts
- High voltage isolation emitter to detector

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_A = 25^\circ\text{C}$ unless otherwise specified)			
Parameter	Symbol	Rating	Unit
Operating Temperature	$T_{OPR}$	-55 to +125	$^\circ\text{C}$
Storage Temperature	$T_{STG}$	-65 to +150	$^\circ\text{C}$
Soldering Temperature (Flow)	$T_{SOL-F}$	260 for 10 sec	$^\circ\text{C}$
<b>EMITTER</b>			
Power Dissipation at 25 $^\circ\text{C}$ Ambient (1)	$P_D$	90	mW
Continuous Forward Current	$I_F$	40	mA
Reverse Voltage	$V_R$	3	V
Forward Current - Peak (1 $\mu\text{s}$ pulse, 300 pps)	$I_F(pk)$	3.0	A
<b>DETECTOR</b>			
Power Dissipation 25 $^\circ\text{C}$ Ambient (2)	$P_D$	200	mW
Collector to Emitter Voltage	$V_{CEO}$	30	V
Emitter to Collector Voltage	$V_{ECO}$	7	V
<b>COUPLER</b>			
Total Power Dissipation (3)	$P_D$	250	mW
Isolation Voltage		1000	VDC

<b>ELECTRICAL / OPTICAL CHARACTERISTICS</b> ( $T_A = 25^\circ\text{C}$ )						
<b>INDIVIDUAL COMPONENT CHARACTERISTICS</b>						
Parameters	Test Conditions	Symbol	Min	Typ	Max	Units
<b>EMITTER</b>						
Forward Voltage	$I_F = 40\text{ mA}$	$V_F$		1.30	1.50	V
Reverse Current	$V_R = 3.0\text{ V}$	$I_R$		0.15	10	$\mu\text{A}$
Capacitance	$V = 0\text{ V}$	C		150		pF
<b>DETECTOR</b>						
Breakdown Voltage Collector to Emitter	$I_C = 1.0\text{ mA}, I_F = 0$	$BV_{CEO}$	30			V
Emitter to Collector	$I_E = 100\ \mu\text{A}, I_F = 0$	$BV_{ECO}$	7	12		V
Leakage Current Collector to Emitter	$V_{CE} = 10\text{ V}, I_F = 0$	$I_{CEO}$		5	50	nA
Capacitance Collector to Emitter	$V_{CE} = 0$	$C_{CE}$		2		pF

**NOTE:**

1. Derate power linearly 1.2 mW/ $^\circ\text{C}$  above 25 $^\circ\text{C}$
2. Derate power linearly 2.67 mW/ $^\circ\text{C}$  above 25 $^\circ\text{C}$
3. Derate power linearly 3.3 mW/ $^\circ\text{C}$  above 25 $^\circ\text{C}$

## MCT4

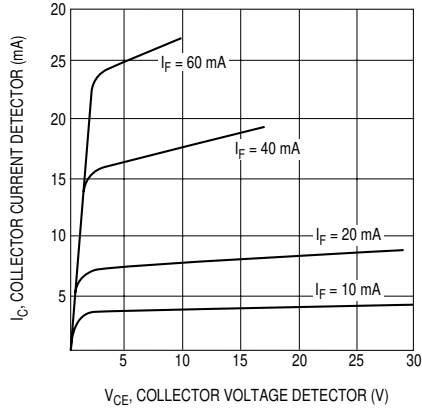
<b>TRANSFER CHARACTERISTICS</b> ( $T_A = 25^\circ\text{C}$ Unless otherwise specified.)						
DC Characteristics	Test Conditions	Symbol	Min	Typ	Max	Units
<b>COUPLED</b>						
DC current Transfer Ratio (note 1)	$V_{CE} = 10\text{ V}, I_F = 10\text{ mA}$	CTR	15	35		%
Saturation Voltage	$I_C = 500\ \mu\text{A}, I_F = 10\text{ mA}$	$V_{CE(SAT)}$		0.1		V
	$I_C = 2\text{ mA}, I_F = 50\text{ mA}$			0.2	0.5	
AC Characteristics	Test Conditions	Symbol	Min	Typ	Max	Units
Capacitance LED to Detector				1.8		pF
Bandwidth (Fig. 5)	Note 2			300		kHz
Rise Time and Fall Time (see operating schematic)	$I_C = 2\text{ mA}, V_{CE} = 10\text{ V}, \text{Note 3}$			2		$\mu\text{s}$

<b>ISOLATION CHARACTERISTICS</b>						
Characteristic	Test Conditions	Symbol	Min	Typ	Max	Units
Isolation Resistance	$V = 500\text{ VDC}$	$R_{ISO}$	$10^{11}$	$10^{12}$		$\Omega$
Breakdown Voltage	Time = 1 sec		1000	1500		VDC

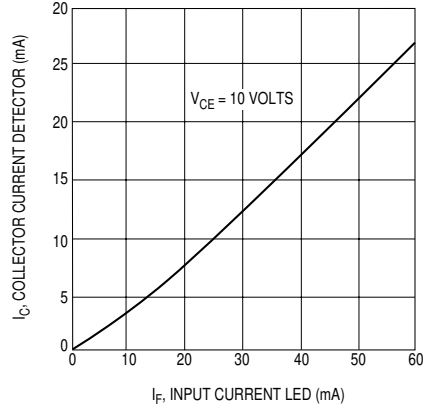
**NOTE:**

1. The current transfer ratio ( $I_C/I_F$ ) is the ratio of the detector collector current to the LED input current with  $V_{CE}$  at 10 volts.
2. The frequency at which  $i_c$  is 3 dB down from the 1 kHz value.
3. Rise time ( $t_r$ ) is the time required for the collector current to increase from 10% of its final value, to 90%. Fall time ( $t_f$ ) is the time required for the collector current to decrease from 90% of its initial value to 10%.

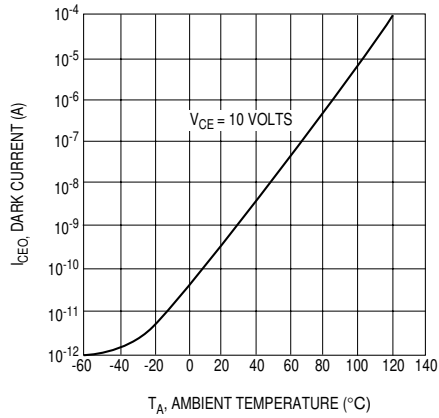
**Figure 1. Detector Output Characteristics**



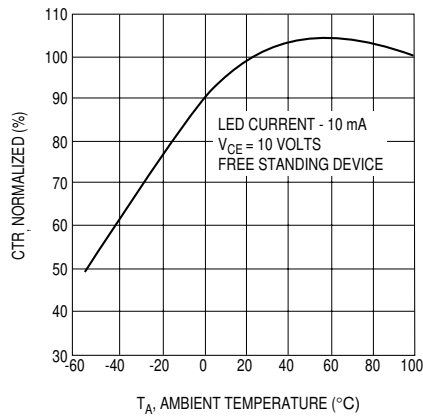
**Figure 2. Input Current vs. Output Current**



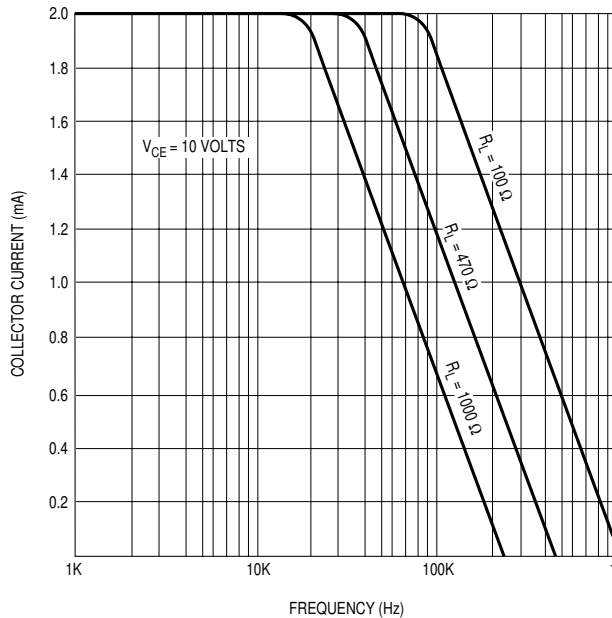
**Figure 3. Dark Current vs. Temperature**



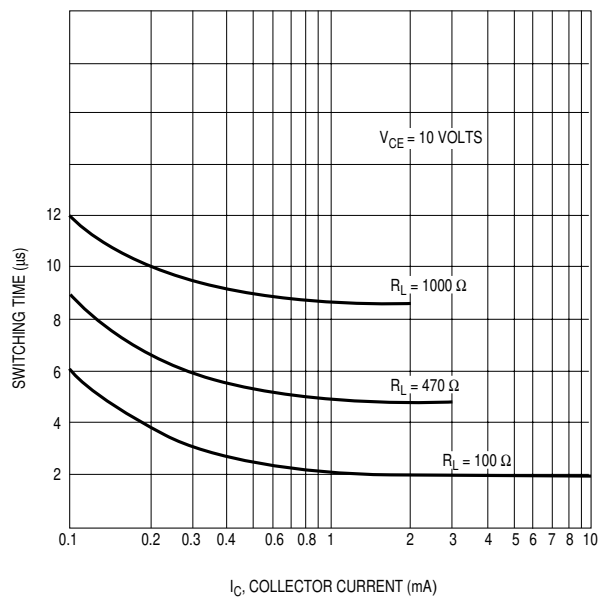
**Figure 4. Current Output vs. Temperature**

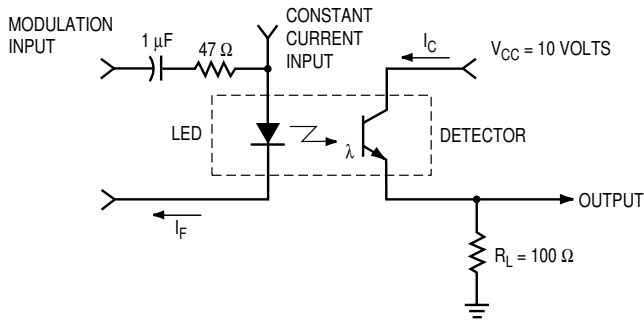


**Figure 5. Output vs. Frequency**

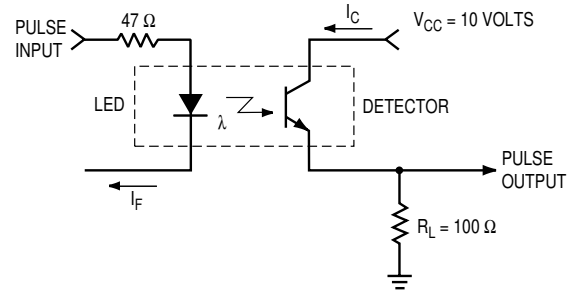


**Figure 6. Switching Time vs. Collector Current**





**Figure 7. Modulation Circuit Used to Obtain Output vs. Frequency Plot**



**Figure 8. Circuit Used to Obtain Switching Time vs. Collector Current Plot**

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